PATENT NUMBER

PATENT DATE O.I.P.E. SCANNED &

CONT/PRIOR CLASS EXAMINER APPLICATION NO. SUBCLASS ART UNIT 121 029 09/833766 3729 Rodrigu 2125 -120

Keiji Emoto

Pipe structure, alignment apparatus, electron beam lithography mapparatus, exposure apparatus, exposure apparatus maintenance method; semiconductor device manufacturing method, and semiconductor manufacturing factory

ISSUING CLASSIFICATION											
ORIGINA	. CROSS REFERENCE(S)										
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)								
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INTERNATIONAL CLASSIFICATION							2.3	in desi			
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TERMINAL		DRAWINGS		CLAIMS ALLOWED			
DISCLAIMER	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.		
☐ The term of this patent				NOTICE OF ALLOWANCE MAILED			
subsequent to (date) has been disclaimed.	(Assistant Examiner) (Date)				•		
The term of this patent shall not extend beyond the expiration date of U.S Patent. No.				ISSUE FEE			
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